

<b>Search Notes</b>				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/611,896	LEE ET AL.	
				Examiner	Art Unit	
				Thien F. Tran	2811	
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
Class	Subclass	Date	Examiner		DATE	EXMR
				Search history printout	2/24/2006	TT
<b>INTERFERENCE SEARCHED</b>						
Class	Subclass	Date	Examiner			